Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/807,293	HASHIGUCHI, AKIHIRO
Examiner	Art Unit
D. Rutledge	2851

	SEARCHED			
Class	Subclass	Date	Examiner	
355	40,85,86	3/19/2005	PR	
101	415.1	3/19/2005	DR	
101	463.1	3/19/2005	DR	
101	477	3/19/2005	DR	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
355	85,86,40	3/19/2005	DR
101	415.1	3/19/2005	DR
101	463.1	3/19/2005	DR
101	477	3/19/2005	DR

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
(first or second) near pair near2 pins and (lateral or reference) near2 pin; exposing or sxposure or printer or printing;	3/19/2005	DR	
punch\$3 same (first or second) near2 pair pins;; punch\$3 same (reference or lateral) near2 pin	3/19/2005	DR	
(first or second) near2 pin	3/19/2005	DR	